

# EE 330

## Lecture 11

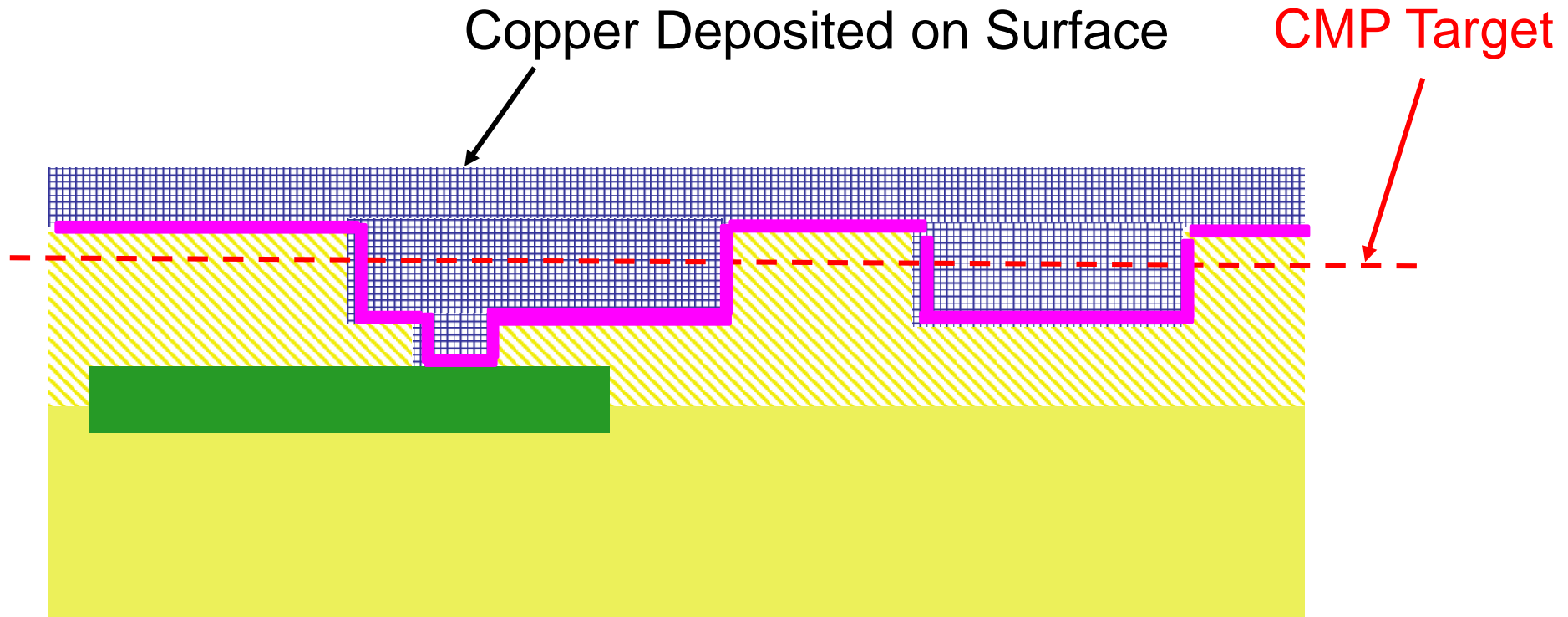
Resistance and Capacitance in Interconnects  
Back-end Processing

# Exam 1      Friday Sept 27

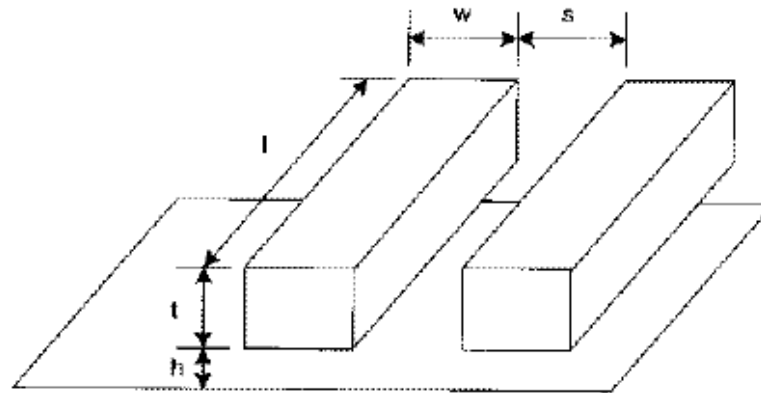
- Students may bring 1 page of notes
- HW assignment for week of Sept 23 due on Wed Sept 25 at beginning of class
- No 5:00 p.m extension so solutions can be posted
- Those with special accommodation needs, please send me an email message or contact me so arrangements can be made
- Review session – to be determined

# Patterning of Copper

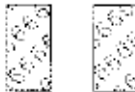
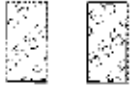




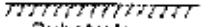
## Dual-Damascene Process



# Interconnect Layers May Vary in Thickness or Be Mostly Uniform



**FIG 4.30** Interconnect geometry

Layer	t(nm)	w(nm)	s(nm)	AR	
6	1720 1000	860	860	2.0	
5	1600 1000	800	800	2.0	
4	1080 700	540	540	2.0	
3	700 700	320	320	2.2	
2	700 700	320	320	2.2	
1	480 800	250	250	1.9	
					 Substrate


12.5μ

**FIG 4.31** Layer stack for 6-metal Intel 180 nm process

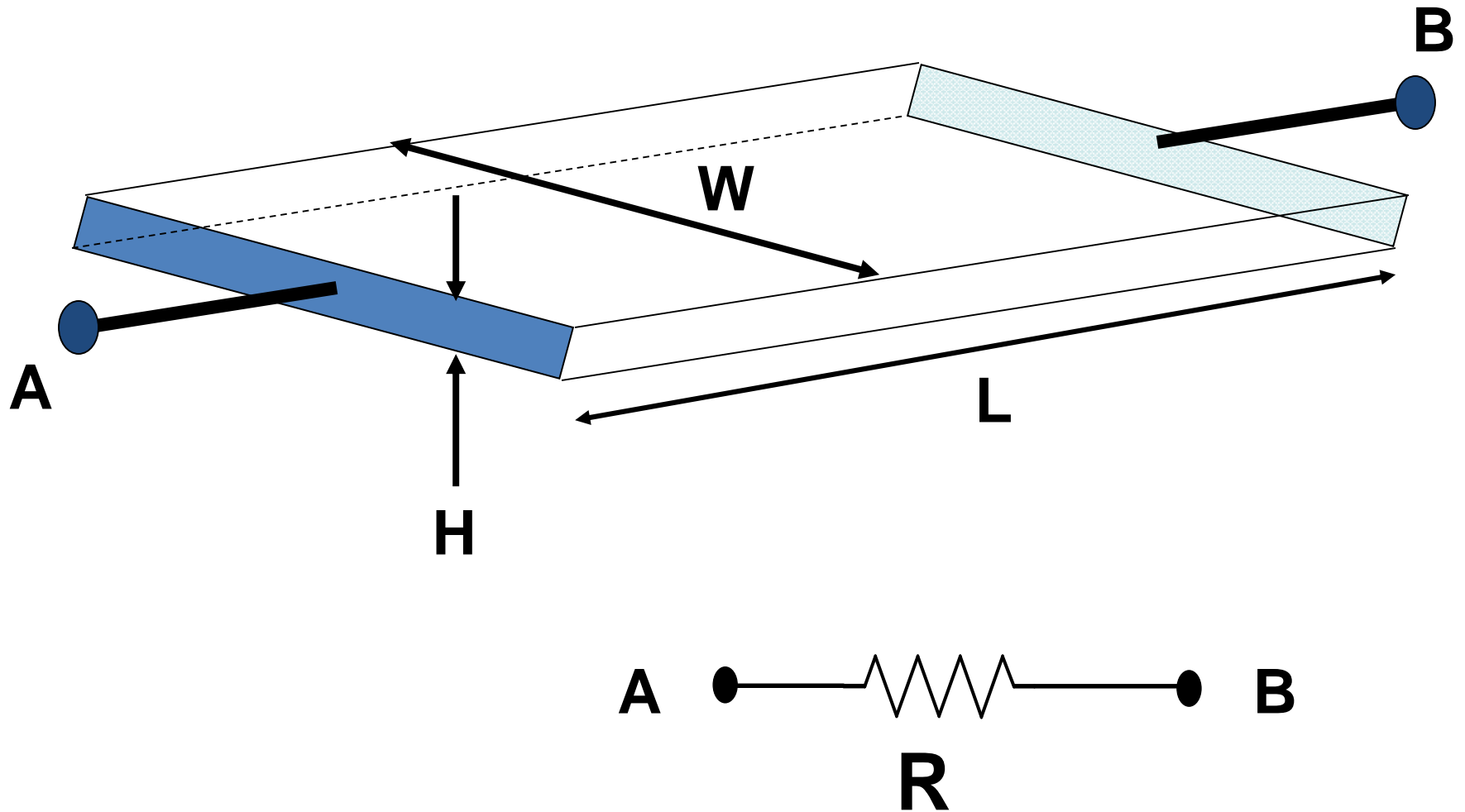
# Interconnects

- Metal is preferred interconnect
  - Because conductivity is high
- Parasitic capacitances and resistances of concern in all interconnects
- Polysilicon used for short interconnects
  - Silicided to reduce resistance
  - Unsilicided when used as resistors
- Diffusion used for short interconnects
  - Parasitic capacitances are high

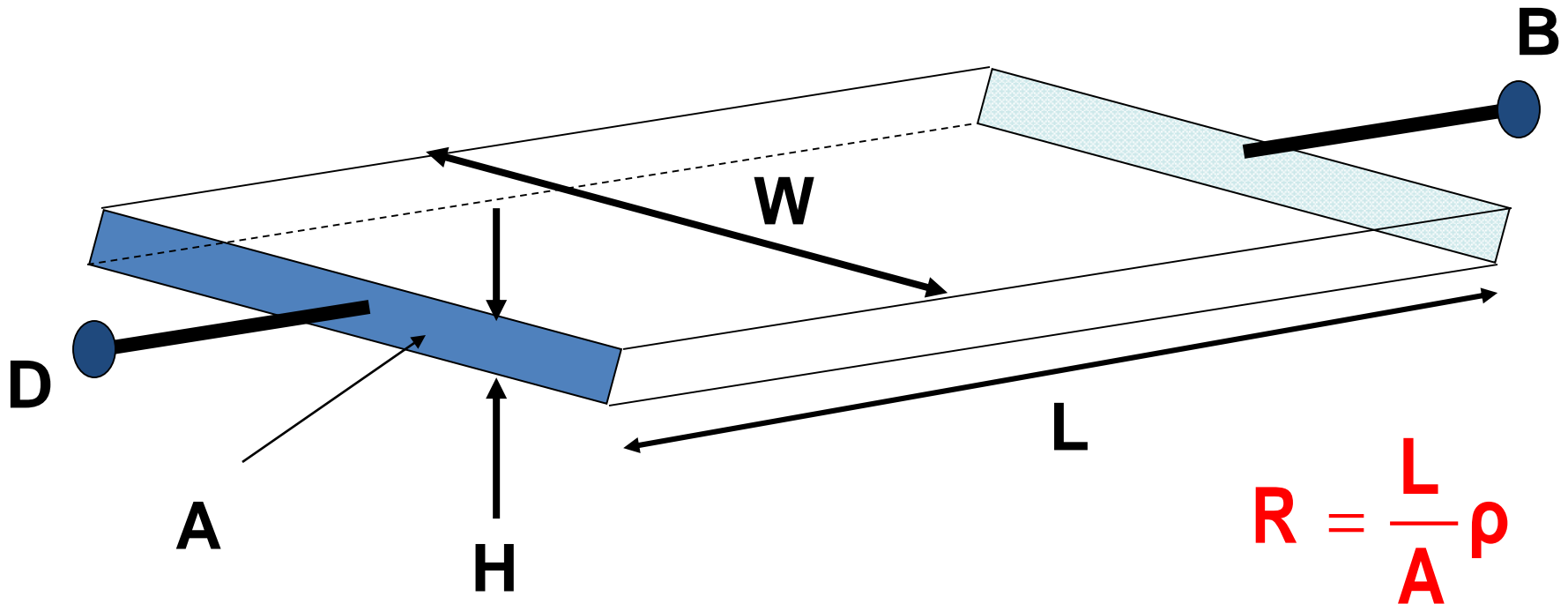
# Interconnects

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  - Parasitic capacitances are high

# Resistance in Interconnects

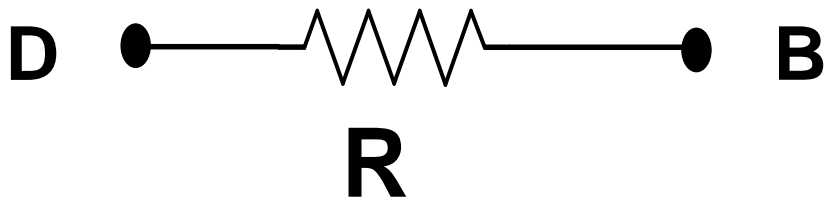


# Resistance in Interconnects



$$R = \frac{L}{A} \rho$$

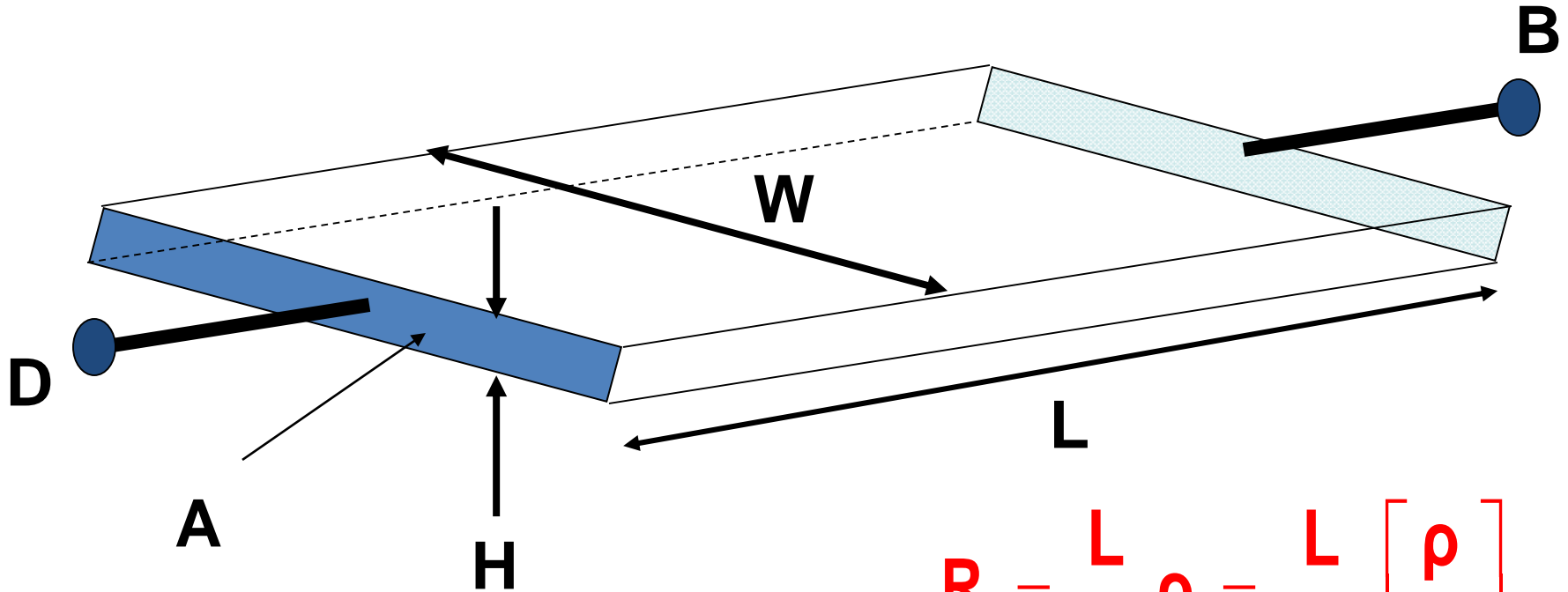
$$A = HW$$



$\rho$  independent of geometry and  
characteristic of the process



# Resistance in Interconnects



$$R = \frac{L}{A} \rho = \frac{L}{W} \left[ \frac{\rho}{H} \right]$$

$H \ll W$  and  $H \ll L$  in most processes

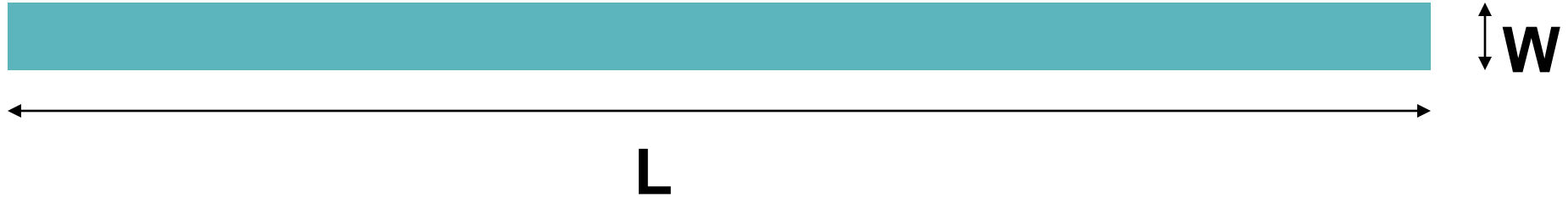
Interconnect behaves as a “thin” film

Sheet resistance often used instead of conductivity to characterize film

$$R_{\square} = \rho / H$$

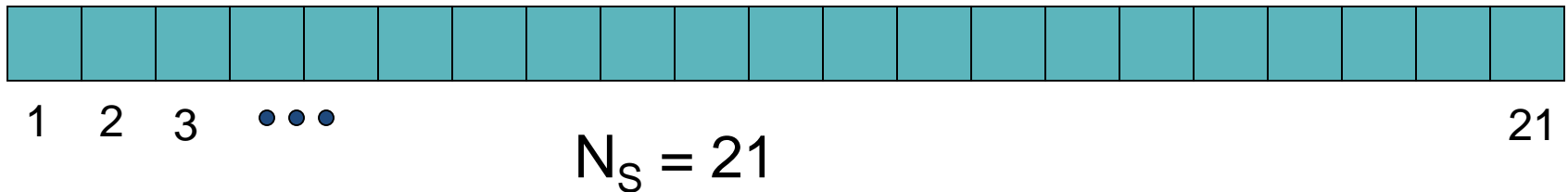
$$R = R_{\square} [L / W]$$

# Resistance in Interconnects



$$R = R_{\square} [L / W]$$

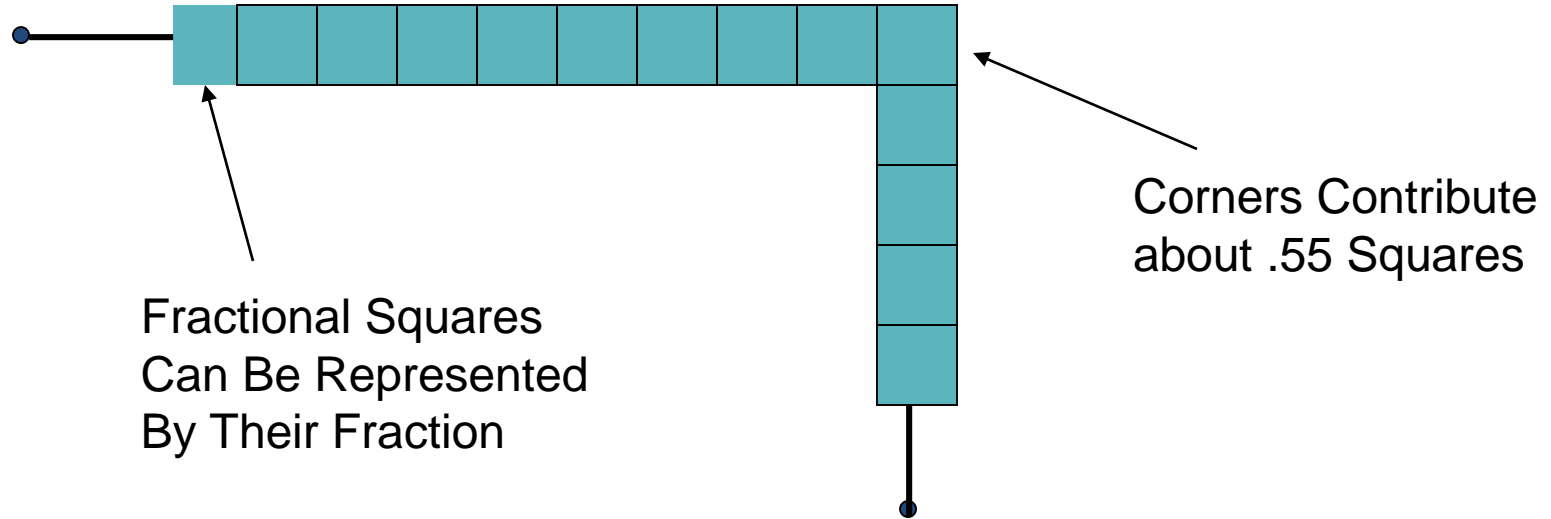
The “Number of Squares” approach to resistance determination in thin films



$$L / W = 21$$

$$R = R_{\square} N_S$$

# Resistance in Interconnects



The “squares” approach is not exact but is good enough for calculating resistance in almost all applications

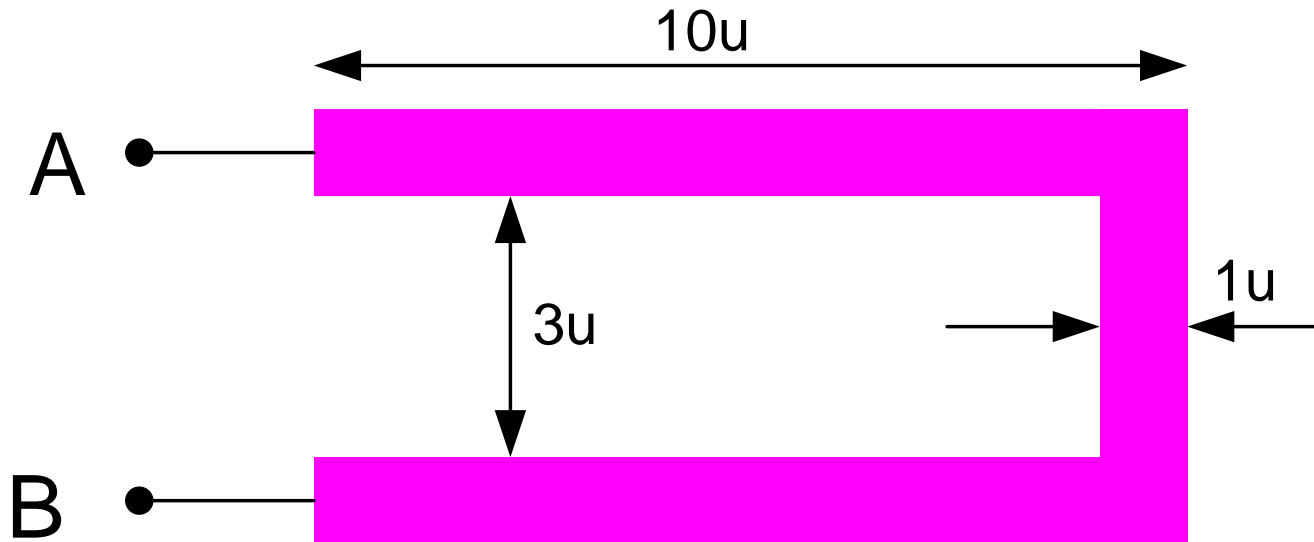
In this example:

$$N_S = 12 + .55 + .7 = 13.25$$

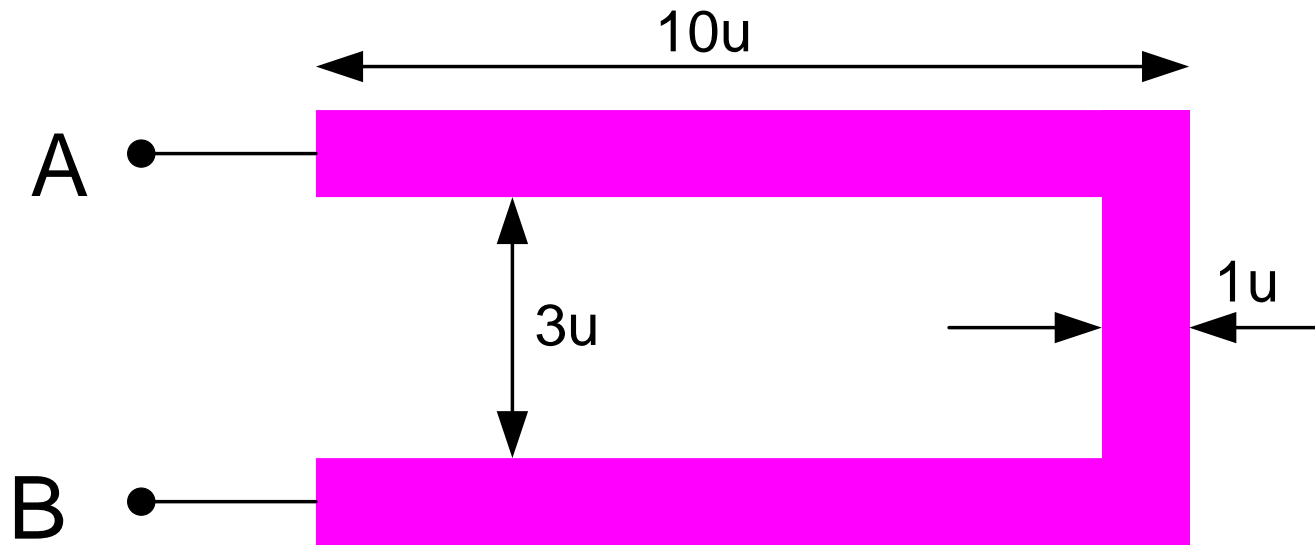
$$R = R_{\square} 13.25$$

## Example:

The layout of a film resistor with electrodes A and B is shown. If the sheet resistance of the film is  $40\ \Omega/\square$ , determine the resistance between nodes A and B.



## Solution

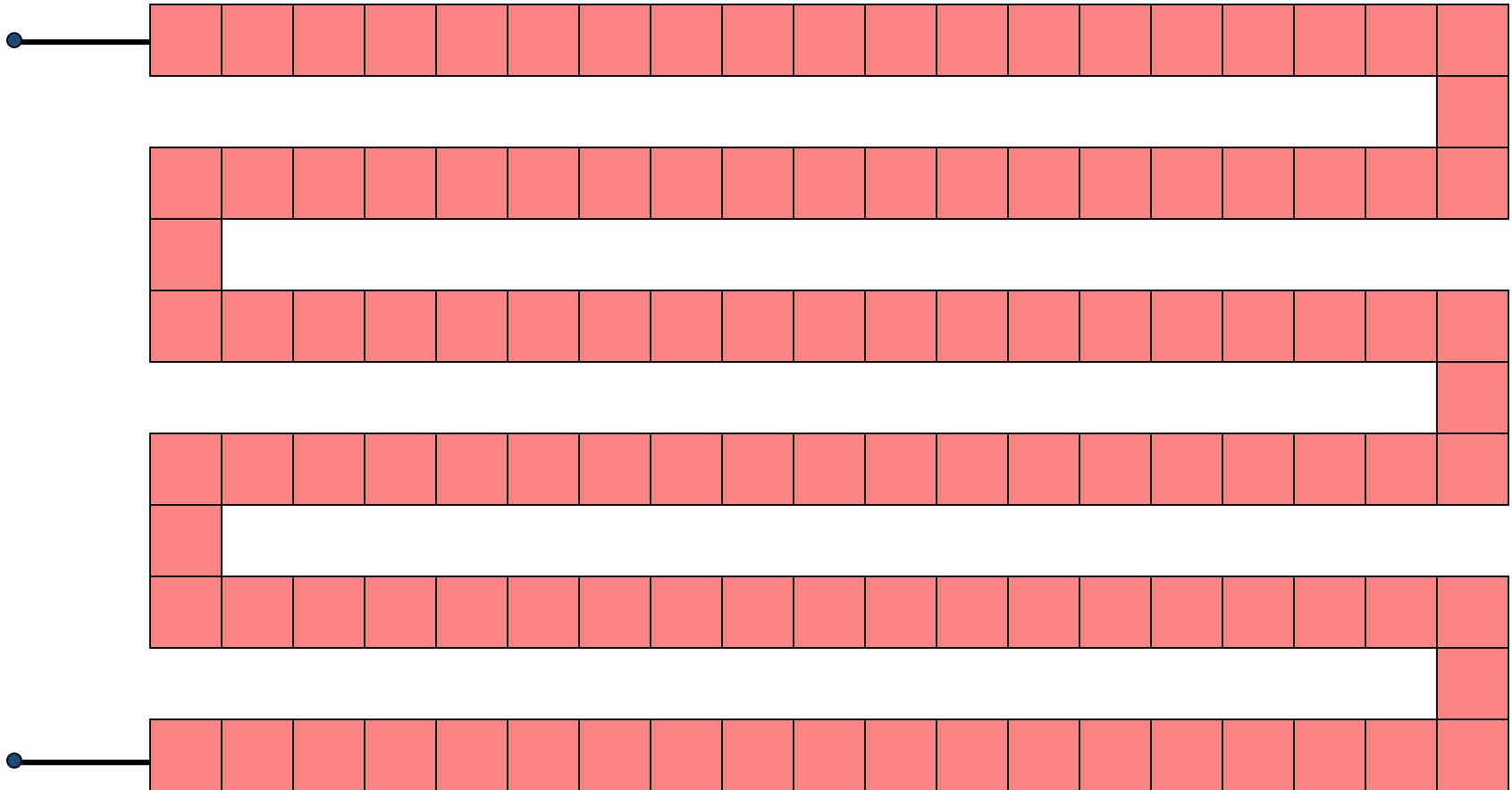


$$N_S = 9 + 9 + 3 + 2(.55) = 22.1$$

$$R_{AB} = R_{\square} N_S = 40 \times 22.1 = 884 \Omega$$

# Resistance in Interconnects

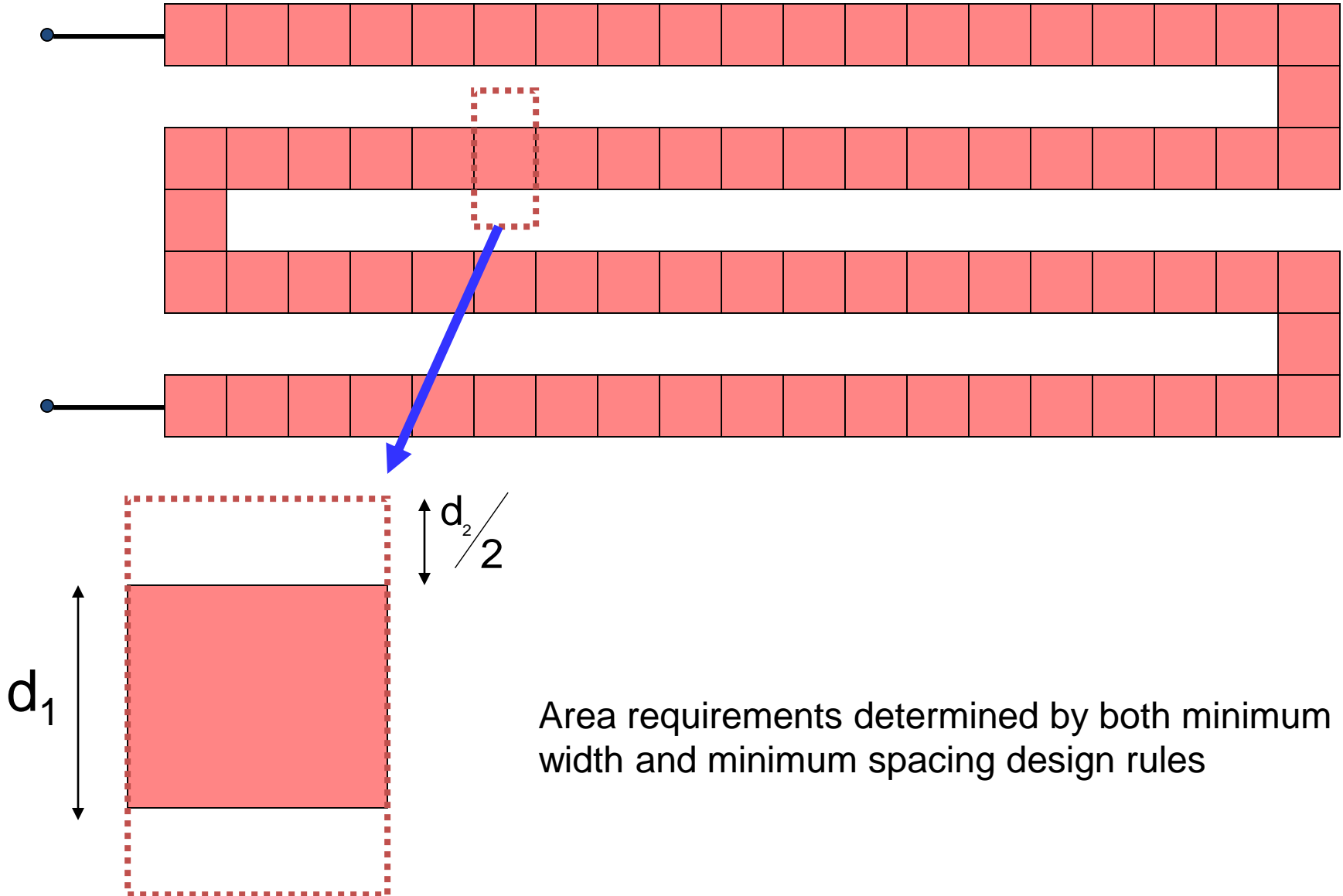
(can be used to build resistors!)



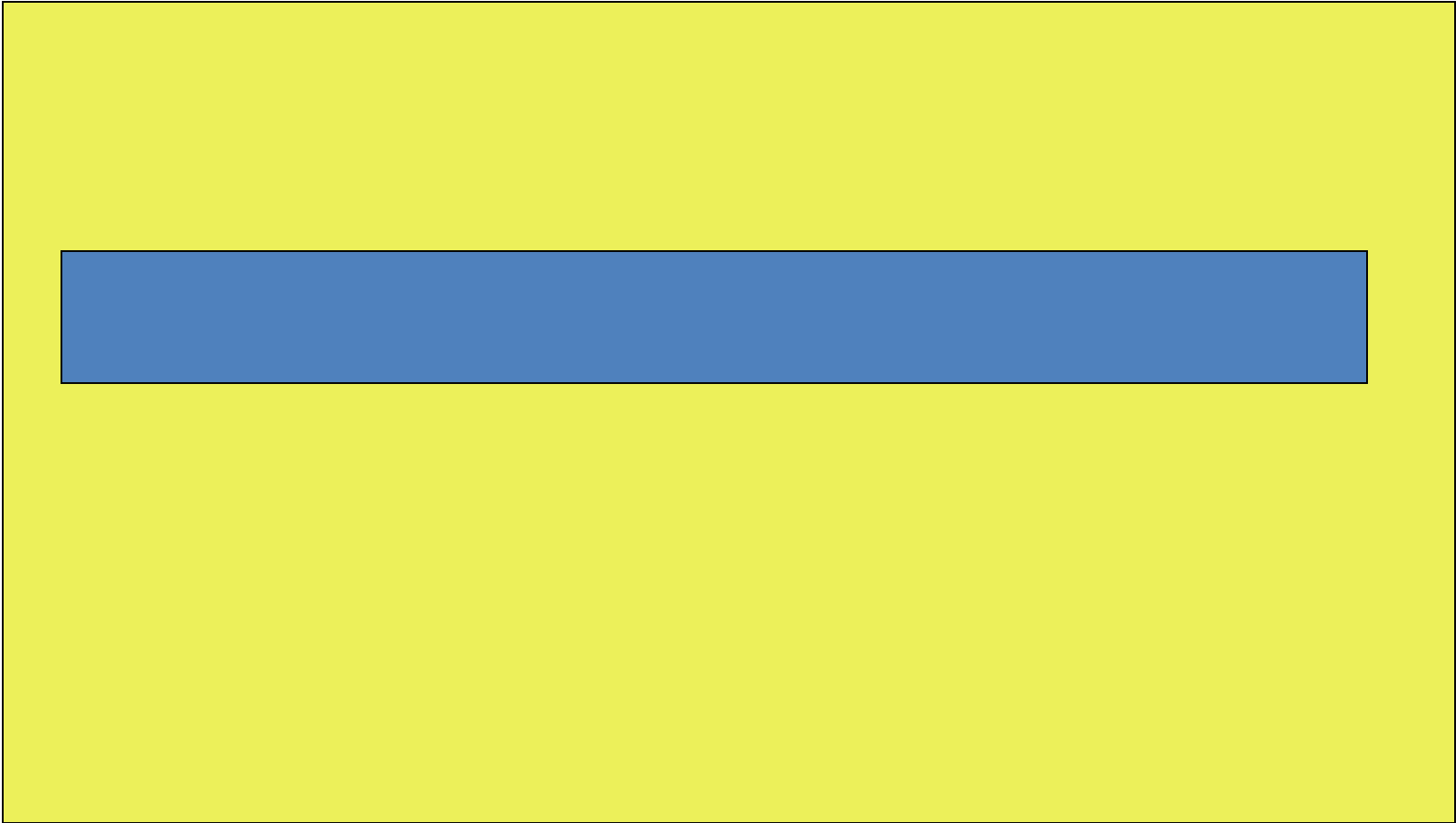
- Serpentine often used when large resistance required
- Polysilicon or diffusion often used for resistor creation
- Effective at managing the aspect ratio of large resistors
- May include hundreds or even thousands of squares

# Resistance in Interconnects

(can be used to build resistors!)



# Capacitance in Interconnects

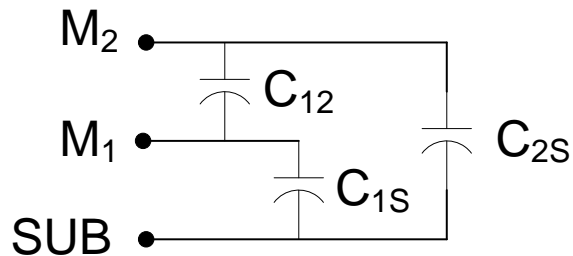
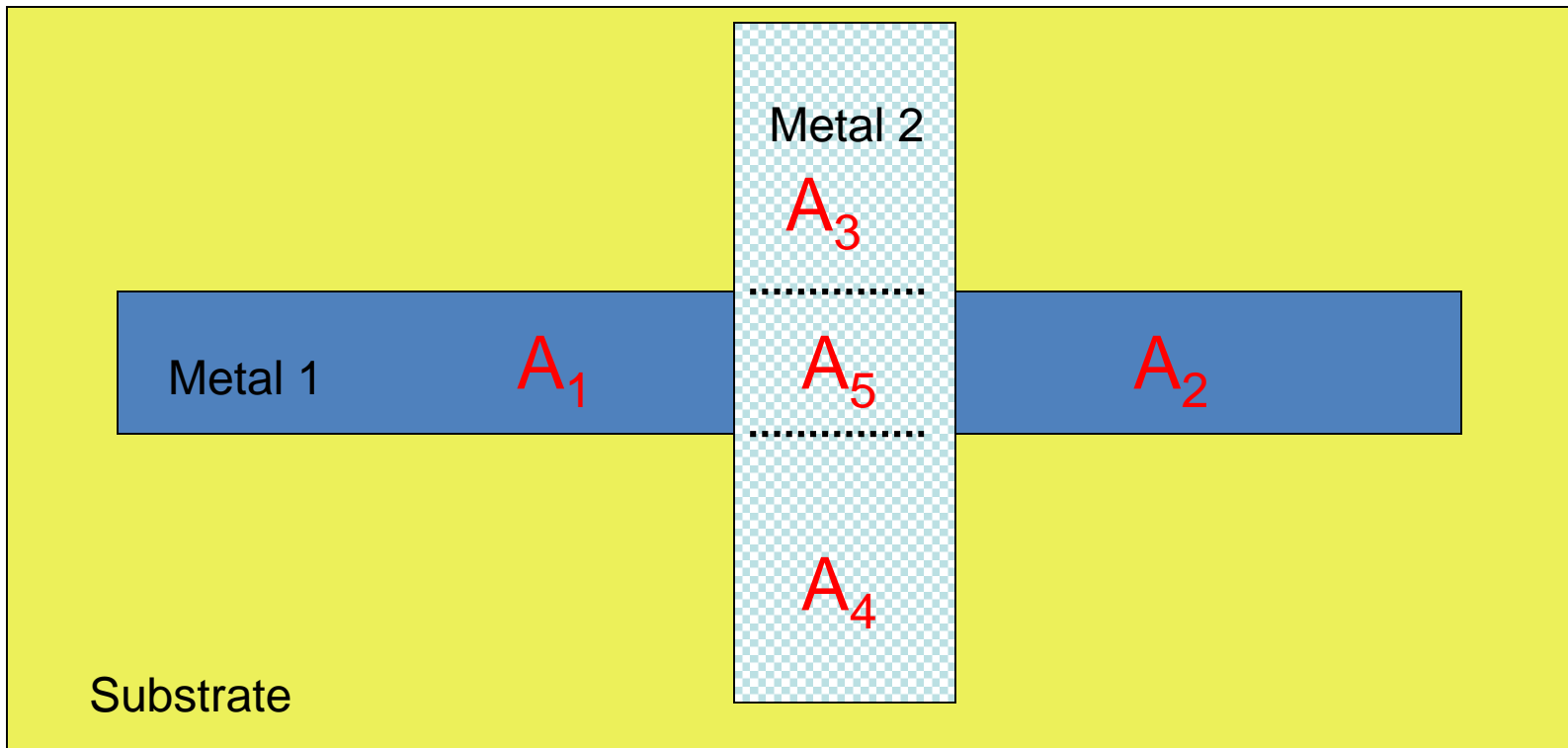


$$C = C_D A$$

$C_D$  is the capacitance density and  $A$  is the area of the overlap



# Capacitance in Interconnects



**Equivalent Circuit**

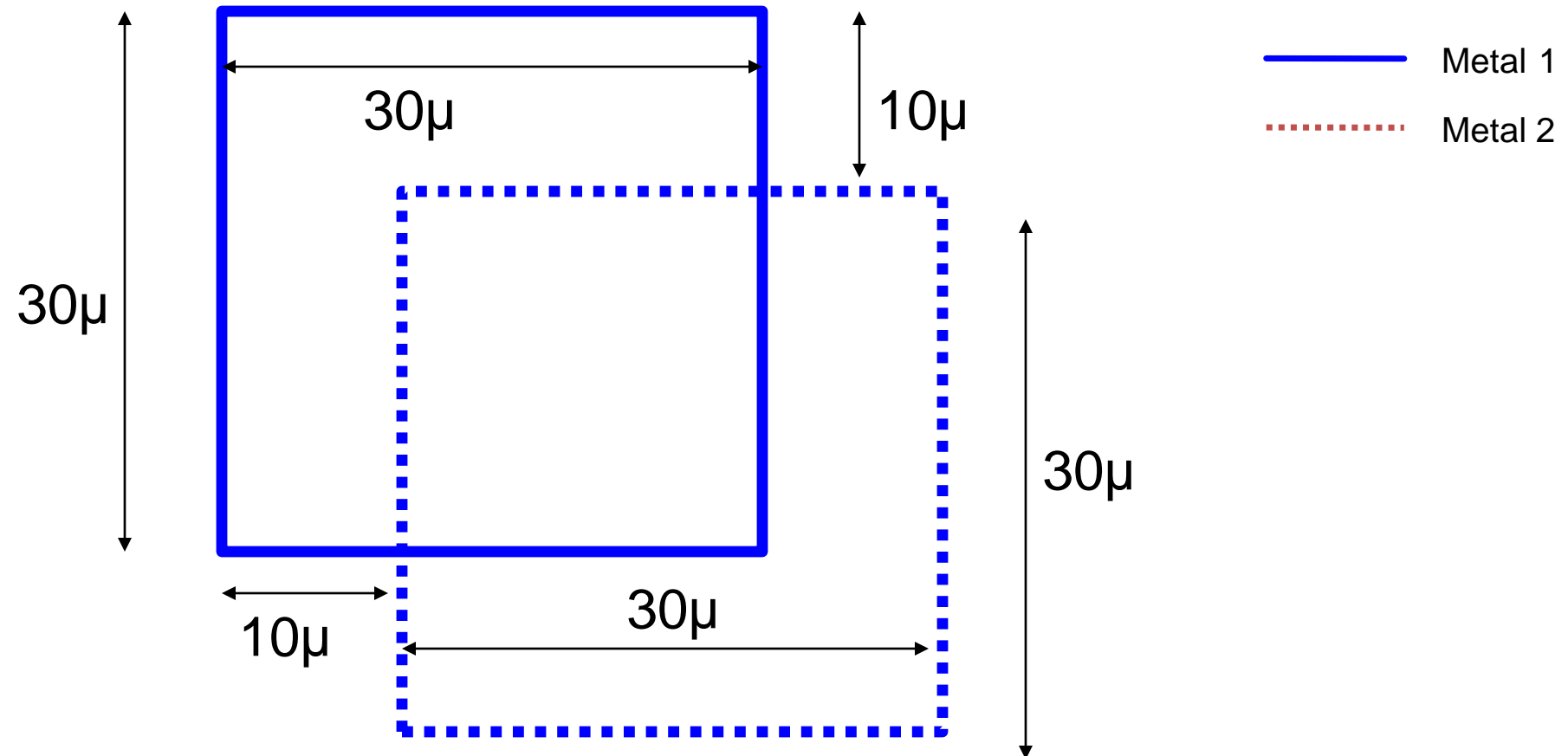
$$C_{12} = CD_{12} A_5$$

$$C_{1S} = CD_{1S} (A_1 + A_2 + A_5)$$

$$C_{2S} = CD_{2S} (A_3 + A_4)$$

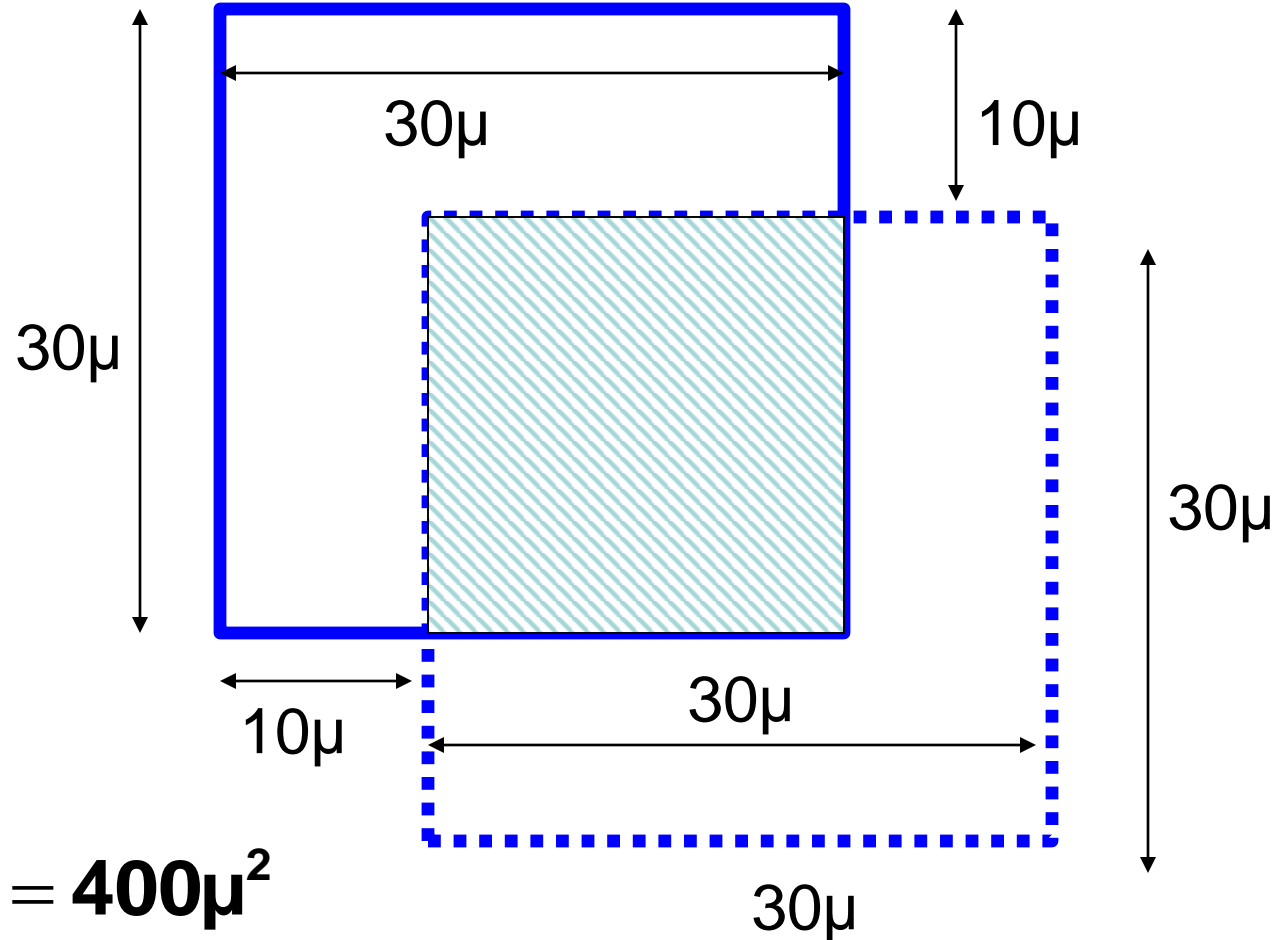
## Example

Two metal layers, Metal 1 and Metal 2, are shown. Both are above field oxide. Determine the capacitance between Metal 1 and Metal 2. Assume the process has capacitance densities from  $M_1$  to substrate of  $.05\text{fF}/\mu^2$ , from  $M_1$  to  $M_2$  of  $.07\text{fF}/\mu^2$  and from  $M_2$  to substrate of  $.025\text{fF}/\mu^2$ .



## Example

Solution



$$A_{C1C2} = (20\mu)^2 = 400\mu^2$$

The capacitance density from  $M_1$  to  $M_2$  is  $.07\text{fF}/\mu^2$

$$C_{12} = A_{C1C2} \bullet C_{D12} = 400\mu^2 \bullet 0.07\text{fF}/\mu^2 = 28\text{fF}$$

# Capacitance and Resistance in Interconnects

- See MOSIS WEB site for process parameters that characterize parasitic resistances and capacitances

[www.mosis.org](http://www.mosis.org)

## MOSIS WAFER ACCEPTANCE TESTS

RUN: T6AU  
TECHNOLOGY: SCN05

Run type: SKD

VENDOR: AMIS  
FEATURE SIZE: 0.5 microns

INTRODUCTION: This report contains the lot average results obtained by MOSIS from measurements of MOSIS test structures on each wafer of this fabrication lot. SPICE parameters obtained from similar measurements on a selected wafer are also attached.

COMMENTS: American Microsystems, Inc. C5

TRANSISTOR PARAMETERS	W/L	N-CHANNEL	P-CHANNEL	UNITS
MINIMUM	3.0/0.6			
Vth		0.79	-0.92	volts
SHORT	20.0/0.6			
Idss		446	-239	uA/um
Vth		0.68	-0.90	volts
Vpt		10.0	-10.0	volts
WIDE	20.0/0.6			
Ids0		< 2.5	< 2.5	pA/um
LARGE	50/50			
Vth		0.68	-0.95	volts
Vjbkd		10.9	-11.6	volts
Ijlk		<50.0	<50.0	pA
Gamma		0.48	0.58	V^0.5
K' (Uo*Cox/2)		56.4	-18.2	uA/V^2
Low-field Mobility		463.87	149.69	cm^2/V*s

COMMENTS: Poly bias varies with design technology. To account for mask bias use the appropriate value for the parameter XL in your SPICE model card.

Design Technology

XL (um) XW (um)

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SCMOS\_SUBM (lambda=0.30)

0.10 0.00

SCMOS (lambda=0.30)

0.00 0.20

# FOX TRANSISTORS

Vth GATE N+ACTIVE P+ACTIVE UNITS

Poly >15.0 <-15.0 volts

## PROCESS PARAMETERS

	N+	P+	POLY	PLY2_HR	POLY2	M1	M2	UNITS
Sheet Resistance	83.5	105.3	23.5	999	44.2	0.09	0.10	ohms/sq
Contact Resistance	64.9	149.7	17.3		29.2		0.97	ohms
Gate Oxide Thickness	142							angstrom

## PROCESS PARAMETERS

	M3	N\PLY	N_W	UNITS
Sheet Resistance	0.05	824	816	ohms/sq
Contact Resistance	0.79			ohms

COMMENTS: N\POLY is N-well under polysilicon.

## CAPACITANCE PARAMETERS

	N+	P+	POLY	POLY2	M1	M2	M3	N_W	UNITS
Area (substrate)	425	731	84		27	12	7	37	aF/um^2
Area (N+active)			2434		35	16	11		aF/um^2
Area (P+active)			2335						aF/um^2
Area (poly)				938	56	15	9		aF/um^2
Area (poly2)					49				aF/um^2
Area (metal1)						31	13		aF/um^2
Area (metal2)							35		aF/um^2
Fringe (substrate)	344	238			49	33	23		aF/um
Fringe (poly)					59	38	28		aF/um
Fringe (metal1)						51	34		aF/um
Fringe (metal2)							52		aF/um
Overlap (N+active)			232						aF/um
Overlap (P+active)			312						aF/um

## CIRCUIT PARAMETERS

	K	UNITS
Inverters		
Vinv	1.0	2.02 volts
Vinv	1.5	2.28 volts
Vol (100 uA)	2.0	0.13 volts

Voh (100 uA)	2.0	4.85	volts
Vinv	2.0	2.46	volts
Gain	2.0	-19.72	
Ring Oscillator Freq.			
DIV256 (31-stg,5.0V)		95.31	MHz
D256_WIDE (31-stg,5.0V)		147.94	MHz
Ring Oscillator Power			
DIV256 (31-stg,5.0V)		0.49	uW/MHz/gate
D256_WIDE (31-stg,5.0V)		1.01	uW/MHz/gate

COMMENTS: SUBMICRON

□ T6AU SPICE BSIM3 VERSION 3.1 PARAMETERS

SPICE 3f5 Level 8, Star-HSPICE Level 49, UTMOST Level 8

\* DATE: Jan 11/07

\* LOT: T6AU

WAF: 7101

\* Temperature\_parameters=Default

```
.MODEL CMOSN NMOS (
+VERSION = 3.1          TNOM    = 27          TOX      = 1.42E-8
+XJ          = 1.5E-7    NCH     = 1.7E17     VTH0     = 0.629035
+K1          = 0.8976376 K2      = -0.09255    K3       = 24.0984767
+K3B         = -8.2369696 W0     = 1.041146E-8 NLX      = 1E-9
+DVT0W       = 0         DVT1W   = 0         DVT2W    = 0
+DVT0        = 2.7123969 DVT1   = 0.4232931 DVT2     = -0.1403765
+U0          = 451.2322004 UA     = 3.091785E-13 UB      = 1.702517E-18
+UC          = 1.22401E-11 VSAT   = 1.715884E5  A0       = 0.6580918
+AGS         = 0.130484  B0     = 2.446405E-6  B1       = 5E-6
+KETA        = -3.043349E-3 A1    = 8.18159E-7  A2       = 0.3363058
+RDSW        = 1.367055E3 PRWG   = 0.0328586  PRWB     = 0.0104806
+WR          = 1         WINT    = 2.443677E-7 LINT     = 6.999776E-8
+XL          = 1E-7      XW      = 0         DWG      = -1.256454E-8
+DWB         = 3.676235E-8 VOFF  = -1.493503E-4 NFACTOR  = 1.0354201
+CIT         = 0         CDSC    = 2.4E-4     CDSCD    = 0
+CDSCB       = 0         ETA0    = 2.342963E-3 ETAB     = -1.5324E-4
+DSUB        = 0.0764123 PCLM   = 2.5941582 PDIBLC1  = 0.8187825
+PDIBLC2     = 2.366707E-3 PDIBLCB = -0.0431505 DROUT    = 0.9919348
+PSCBE1      = 6.611774E8 PSCBE2 = 3.238266E-4 PVAG     = 0
+DELTA       = 0.01     RSH     = 83.5     MOBMOD   = 1
```

+PRT	= 0	UTE	= -1.5	KT1	= -0.11
+KT1L	= 0	KT2	= 0.022	UA1	= 4.31E-9
+UB1	= -7.61E-18	UC1	= -5.6E-11	AT	= 3.3E4
+WL	= 0	WLN	= 1	WW	= 0
+WWN	= 1	WWL	= 0	LL	= 0
+LLN	= 1	LW	= 0	LWN	= 1
+LWL	= 0	CAPMOD	= 2	XPART	= 0.5
+CGDO	= 2.32E-10	CGSO	= 2.32E-10	CGBO	= 1E-9
+CJ	= 4.282017E-4	PB	= 0.9317787	MJ	= 0.4495867
+CJSW	= 3.034055E-10	PBSW	= 0.8	MJSW	= 0.1713852
+CJSWG	= 1.64E-10	PBSWG	= 0.8	MJSWG	= 0.1713852
+CF	= 0	PVTH0	= 0.0520855	PRDSW	= 112.8875816
+PK2	= -0.0289036	WKETA	= -0.0237483	LKETA	= 1.728324E-3
*)					
* .MODEL CMOS PMOS (					
+VERSION	= 3.1	TNOM	= 27	LEVEL	= 49
+XJ	= 1.5E-7	NCH	= 1.7E17	TOX	= 1.42E-8
+K1	= 0.5464347	K2	= 8.119291E-3	VTH0	= -0.9232867
+K3B	= -0.8373484	W0	= 1.30945E-8	K3	= 5.1623206
+DVT0W	= 0	DVT1W	= 0	NLX	= 5.772187E-8
+DVT0	= 2.0973823	DVT1	= 0.5356454	DVT2W	= 0
+U0	= 220.5922586	UA	= 3.144939E-9	DVT2	= -0.1185455
+UC	= -6.19354E-11	VSAT	= 1.176415E5	UB	= 1E-21
+AGS	= 0.1447245	B0	= 1.149181E-6	A0	= 0.8441929
+KETA	= -1.093365E-3	A1	= 3.467482E-4	B1	= 5E-6
+RDSW	= 3E3	PRWG	= -0.0418549	A2	= 0.4667486
+WR	= 1	WINT	= 3.007497E-7	PRWB	= -0.0212201
+XL	= 1E-7	XW	= 0	LINT	= 1.040439E-7
+DWB	= 1.706031E-8	VOFF	= -0.0801591	DWG	= -2.133809E-8
+CIT	= 0	CDSC	= 2.4E-4	NFACTOR	= 0.9468597
+CDSCB	= 0	ETA0	= 0.4060383	CDSCD	= 0
+DSUB	= 1	PCLM	= 2.2703293	ETAB	= -0.0633609
+PDIBLC2	= 3.201161E-3	PDIBLCB	= -0.057478	PDIBLC1	= 0.0279014
+PSCBE1	= 4.876974E9	PSCBE2	= 5E-10	DROUT	= 0.1718548
+DELTA	= 0.01	RSH	= 105.3	PVAG	= 0
+PRT	= 0	UTE	= -1.5	MOBMOD	= 1
+KT1L	= 0	KT2	= 0.022	KT1	= -0.11
+UB1	= -7.61E-18	UC1	= -5.6E-11	UA1	= 4.31E-9
+WL	= 0	WLN	= 1	AT	= 3.3E4
+WWN	= 1	WWL	= 0	WW	= 0
+LLN	= 1	LW	= 0	LL	= 0
+LWL	= 0	CAPMOD	= 2	LWN	= 1
+CGDO	= 3.12E-10	CGSO	= 3.12E-10	XPART	= 0.5
				CGBO	= 1E-9



+CJ	= 7.254264E-4	PB	= 0.9682229	MJ	= 0.4969013
+CJSW	= 2.496599E-10	PBSW	= 0.99	MJSW	= 0.386204
+CJSWG	= 6.4E-11	PBSWG	= 0.99	MJSWG	= 0.386204
+CF	= 0	PVTH0	= 5.98016E-3	PRDSW	= 14.8598424
+PK2	= 3.73981E-3	WKETA	= 7.286716E-4	LKETA	= -4.768569E-3

★

# MOSIS WAFER ACCEPTANCE TESTS

RUN: T4BK (MM\_NON-EPI\_THK-MTL)  
TECHNOLOGY: SCN018

VENDOR: TSMC  
FEATURE SIZE: 0.18 microns

INTRODUCTION: This report contains the lot average results obtained by MOSIS from measurements of MOSIS test structures on each wafer of this fabrication lot. SPICE parameters obtained from similar measurements on a selected wafer are also attached.

COMMENTS: DSCN6M018\_TSMC

TRANSISTOR PARAMETERS	W/L	N-CHANNEL	P-CHANNEL	UNITS
MINIMUM	0.27/0.18			
Vth		0.50	-0.53	volts
SHORT	20.0/0.18			
Idss		571	-266	uA/um
Vth		0.51	-0.53	volts
Vpt		4.7	-5.5	volts
WIDE	20.0/0.18			
Ids0		22.0	-5.6	pA/um
LARGE	50/50			
Vth		0.42	-0.41	volts
Vjblk		3.1	-4.1	volts
Ijlk		<50.0	<50.0	pA
K' (Uo*Cox/2)		171.8	-36.3	uA/V^2
Low-field Mobility		398.02	84.10	cm^2/V*s

COMMENTS: Poly bias varies with design technology. To account for mask bias use the appropriate value for the parameters XL and XW in your SPICE model card.

FOX TRANSISTORS	GATE	N+ACTIVE	P+ACTIVE	UNITS
Vth	Poly	>6.6	<-6.6	volts



# T4BK SPICE BSIM3 VERSION 3.1 PARAMETERS

SPICE 3f5 Level 8, Star-HSPICE Level 49, UTMOST Level 8

\* DATE: Jan 21/05

\* LOT: T4BK

WAF: 3004

\* Temperature\_parameters=Default

.MODEL CMOSN NMOS (

+VERSION = 3.1	TNOM = 27	LEVEL = 49
+XJ = 1E-7	NCH = 2.3549E17	TOX = 4E-9
+K1 = 0.5802748	K2 = 3.124029E-3	VTH0 = 0.3662648
+K3B = 3.3886871	W0 = 1E-7	K3 = 1E-3
+DVT0W = 0	DVT1W = 0	NLX = 1.766159E-7
+DVT0 = 1.2312416	DVT1 = 0.3849841	DVT2W = 0
+U0 = 265.1889031	UA = -1.506402E-9	DVT2 = 0.0161351
+UC = 5.621884E-11	VSAT = 1.017932E5	UB = 2.489393E-18
+AGS = 0.4543117	B0 = 3.433489E-7	A0 = 2
+KETA = -0.0127714	A1 = 1.158074E-3	B1 = 5E-6
+RDSW = 136.5582806	PRWG = 0.5	A2 = 1
+WR = 1	WINT = 0	PRWB = -0.2
+XL = 0	XW = -1E-8	LINT = 1.702415E-8
+DWB = 1.107719E-8	VOFF = -0.0948017	DWG = -4.211574E-9
+CIT = 0	CDSC = 2.4E-4	NFACTOR = 2.1860065
+CDSCB = 0	ETA0 = 3.335516E-3	CDSCD = 0
+DSUB = 0.0214781	PCLM = 0.6602119	ETAB = 6.028975E-5
+PDIBLC2 = 3.287142E-3	PDIBLCB = -0.1	PDIBLC1 = 0.1605325
+PSCBE1 = 6.420235E9	PSCBE2 = 4.122516E-9	DROUT = 0.7917811
+DELTA = 0.01	RSH = 6.6	PVAG = 0.0347169
+PRT = 0	UTE = -1.5	MOBMOD = 1
+KT1L = 0	KT2 = 0.022	KT1 = -0.11
+UB1 = -7.61E-18	UC1 = -5.6E-11	UA1 = 4.31E-9
+WL = 0	WLN = 1	AT = 3.3E4
+WWN = 1	WWL = 0	WW = 0
+LLN = 1	LW = 0	LL = 0
+LWL = 0	CAPMOD = 2	LWN = 1
+CGDO = 8.06E-10	CGSO = 8.06E-10	XPART = 0.5
+CJ = 9.895609E-4	PB = 0.8	CGBO = 1E-12
+CJSW = 2.393608E-10	PBSW = 0.8	MJ = 0.3736889
+CJSWG = 3.3E-10	PBSWG = 0.8	MJSW = 0.1537892
+CF = 0	PVTH0 = -1.73163E-3	MJSWG = 0.1537892
+PK2 = 1.600729E-3	WKETA = 1.601517E-3	PRDSW = -1.4173554
+PU0 = 5.2024473	PUA = 1.584315E-12	LKETA = -3.255127E-3
+PVSAT = 1.686297E3	PETA0 = 1.001594E-4	PUB = 7.446142E-25
		PKETA = -2.039532E-3

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.MODEL CMOSP PMOS (
+VERSION = 3.1          TNOM    = 27          TOX      = 4E-9
+XJ       = 1E-7        NCH     = 4.1589E17    VTH0     = -0.3708038
+K1       = 0.5895473   K2      = 0.0235946    K3       = 0
+K3B      = 13.8642028  W0      = 1E-6      NLX      = 1.517201E-7
+DVT0W    = 0          DVT1W   = 0          DVT2W    = 0
+DVT0     = 0.7885088  DVT1   = 0.2564577    DVT2     = 0.1
+U0       = 103.0478426 UA      = 1.049312E-9    UB       = 2.545758E-21
+UC       = -1E-10     VSAT    = 1.645114E5    A0       = 1.627879
+AGS      = 0.3295499  B0      = 5.207699E-7    B1       = 1.370868E-6
+KETA     = 0.0296157  A1      = 0.4449009    A2       = 0.3
+RDSW     = 306.5789827 PRWG    = 0.5          PRWB     = 0.5
+WR       = 1          WINT    = 0          LINT     = 2.761033E-8
+XL       = 0          XW      = -1E-8      DWG      = -2.433889E-8
+DWB      = -9.34648E-11 VOFF    = -0.0867009    NFACTOR  = 2
+CIT       = 0         CDSC     = 2.4E-4      CDSCD    = 0
+CDSCB    = 0         ETA0     = 1.018318E-3    ETAB     = -3.206319E-4
+DSUB     = 1.094521E-3 PCLM    = 1.3281073    PDIBLC1  = 2.394169E-3
+PDIBLC2  = -3.255915E-6 PDIBLCB = -1E-3      DROUT    = 0
+PSCBE1   = 4.881933E10 PSCBE2  = 5E-10      PVAG     = 2.0932623

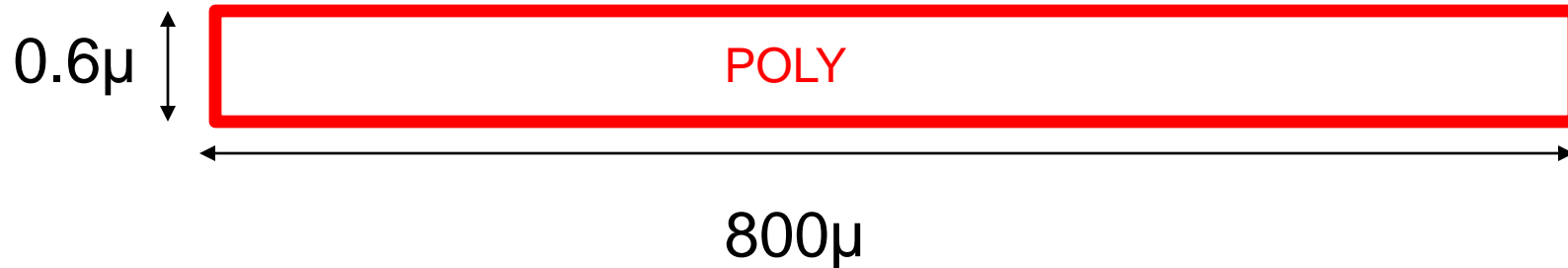
+DELTA    = 0.01       RSH     = 7.5          MOBMOD   = 1
+PRT       = 0         UTE     = -1.5        KT1      = -0.11
+KT1L     = 0         KT2     = 0.022       UA1      = 4.31E-9
+UB1      = -7.61E-18 UC1     = -5.6E-11    AT       = 3.3E4
+WL       = 0         WLN     = 1          WW      = 0
+WWN      = 1         WWL     = 0          LL      = 0
+LLN      = 1         LW      = 0          LWN     = 1
+LWL      = 0         CAPMOD  = 2          XPART   = 0.5
+CGDO     = 6.52E-10  CGSO    = 6.52E-10    CGBO    = 1E-12
+CJ       = 1.157423E-3 PB      = 0.8444261    MJ       = 0.4063933
+CJSW     = 1.902456E-10 PBSW    = 0.8          MJSW    = 0.3550788
+CJSWG    = 4.22E-10  PBSWG   = 0.8          MJSWG   = 0.3550788
+CF       = 0         PVTH0   = 1.4398E-3    PRDSW   = 0.5073407
+PK2      = 2.190431E-3 WKETA   = 0.0442978    LKETA   = -2.936093E-3
+PU0      = -0.9769623 PUA     = -4.34529E-11 PUB      = 1E-21
+PVSAT    = -50       PETA0   = 1.002762E-4 PKETA    = -6.740436E-3 )

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## Example

Determine the resistance and capacitance of a Poly interconnect that is 0.6u wide and 800u long and compare that with the same interconnect if M<sub>1</sub> were used. Assume a 0.5u process.



$$R_{\text{POLY}} = n_{\text{SQ}} R_{\text{SH}}$$

$$C_{\text{P-SUB}} = A \cdot C_{\text{DPS}}$$

$$R_{\text{SH}} = ?$$

$$R_{\text{DPS}} = ?$$

For 0.5u process

SCMOS_SUBM (lambda=0.30)	0.10	0.00
SCMOS (lambda=0.35)	0.00	0.20

FOX TRANSISTORS	GATE	N+ACTIVE	P+ACTIVE	UNITS
Vth	Poly	>15.0	<-15.0	volts

$$R_{SH} = 23.5 \Omega/\square$$

PROCESS PARAMETERS	N+	P+	POLY	PLY2_HR	POLY2	M1	M2	UNITS
Sheet Resistance	83.5	105.3	23.5	999	44.2	0.09	0.10	ohms/sq
Contact Resistance	64.9	149.7	17.3		29.2		0.97	ohms
Gate Oxide Thickness	142							angstrom

PROCESS PARAMETERS	M3	N\PLY	N_W	UNITS
Sheet Resistance	0.05	824	816	ohms/sq
Contact Resistance	0.79			ohms

COMMENTS: N\POLY is N-well under polysilicon.

$$C_{DPS} = 84 \text{ af}/\mu^2$$

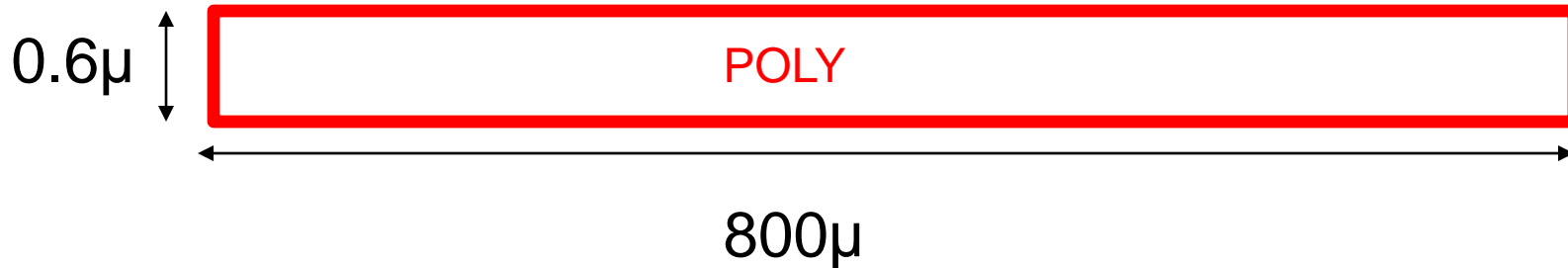
CAPACITANCE PARAMETERS	N+	P+	POLY	POLY2	M1	M2	M3	N_W	UNITS
Area (substrate)	425	731	84		27	12	7	37	aF/um^2
Area (N+active)			2434		35	16	11		aF/um^2
Area (P+active)			2335						aF/um^2
Area (poly)				938	56	15	9		aF/um^2
Area (poly2)					49				aF/um^2
Area (metal1)						31	13		aF/um^2
Area (metal2)							35		aF/um^2
Fringe (substrate)	344	238			49	33	23		aF/um
Fringe (poly)					59	38	28		aF/um
Fringe (metal1)						51	34		aF/um
Fringe (metal2)							52		aF/um
Overlap (N+active)			232						aF/um
Overlap (P+active)			312						aF/um

CIRCUIT PARAMETERS			UNITS
Inverters	K		
Vinv	1.0	2.02	volts
Vinv	1.5	2.28	volts
Vol (100 uA)	2.0	0.13	volts

## Example

For 0.5u process

Determine the resistance and capacitance of a Poly interconnect that is 0.6u wide and 800u long and compare that with the same interconnect if M<sub>1</sub> were used.



$$n_{sq} = \frac{800\mu}{0.6\mu} = 1333$$

$$A = (0.6\mu)(800\mu) = 480\mu^2$$

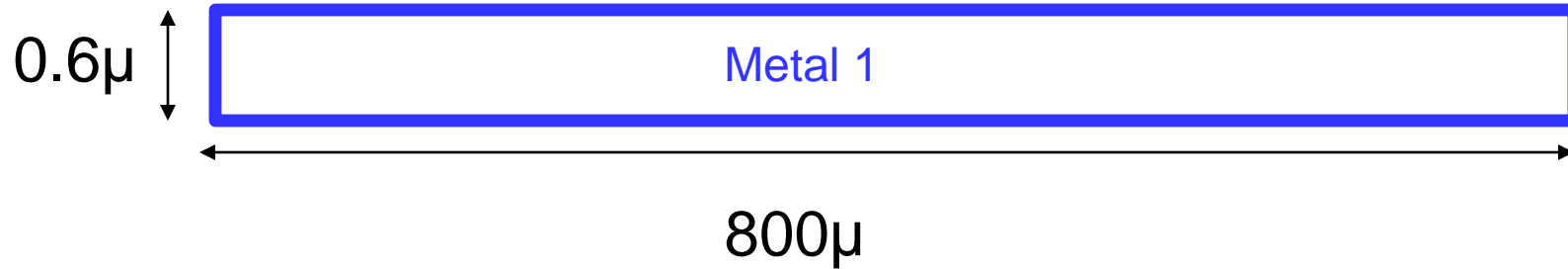
$$R_{POLY} = n_{SQ} R_{SH} = 7.7 \cdot 1333 = 10.3K\Omega$$

$$C_{P-SUB} = A \cdot C_{DPS} = 480\mu^2 \cdot 103aF\mu^{-2} = 49.4fF$$



## Example

Determine the resistance and capacitance of a Poly interconnect that is  $0.6\mu$  wide and  $800\mu$  long and compare that with the same interconnect if  $M_1$  were used.



For 0.5u process

SCMOS_SUBM (lambda=0.30)	0.10	0.00
SCMOS (lambda=0.35)	0.00	0.20

FOX TRANSISTORS	GATE	N+ACTIVE	P+ACTIVE	UNITS
Vth	Poly	>15.0	<-15.0	volts

$$R_{SH} = 0.09 \Omega/\square$$

PROCESS PARAMETERS	N+	P+	POLY	PLY2_HR	POLY2	M1	M2	UNITS
Sheet Resistance	83.5	105.3	23.5	999	44.2	0.09	0.10	ohms/sq
Contact Resistance	64.9	149.7	17.3		29.2		0.97	ohms
Gate Oxide Thickness	142							angstrom

PROCESS PARAMETERS	M3	N\PLY	N_W	UNITS
Sheet Resistance	0.05	824	816	ohms/sq
Contact Resistance	0.79			ohms

COMMENTS: N\POLY is N-well under polysilicon.

$$C_{DPS} = 27 \text{ af}/\mu^2$$

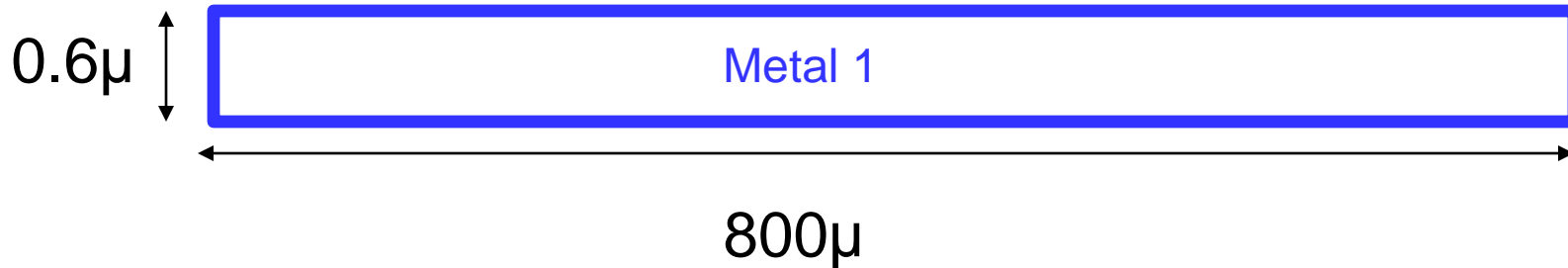
CAPACITANCE PARAMETERS	N+	P+	POLY	POLY2	M1	M2	M3	N_W	UNITS
Area (substrate)	425	731	84		27	12	7	37	aF/um^2
Area (N+active)			2434		35	16	11		aF/um^2
Area (P+active)			2335						aF/um^2
Area (poly)				938	56	15	9		aF/um^2
Area (poly2)					49				aF/um^2
Area (metal1)						31	13		aF/um^2
Area (metal2)							35		aF/um^2
Fringe (substrate)	344	238			49	33	23		aF/um
Fringe (poly)					59	38	28		aF/um
Fringe (metal1)						51	34		aF/um
Fringe (metal2)							52		aF/um
Overlap (N+active)			232						aF/um
Overlap (P+active)			312						aF/um

CIRCUIT PARAMETERS			UNITS
Inverters	K		
Vinv	1.0	2.02	volts
Vinv	1.5	2.28	volts
Vol (100 uA)	2.0	0.13	volts

## Example

For 0.5u process

Determine the resistance and capacitance of a Poly interconnect that is 0.6u wide and 800u long and compare that with the same interconnect if M<sub>1</sub> were used.



$$n_{sq} = \frac{800\mu}{0.6\mu} = 1333 \quad A = (0.6\mu)(800\mu) = 480\mu^2$$

$$R_{M1} = n_{SQ} R_{SH} = 0.09 \cdot 1333 = 120\Omega$$

$$C_{M1-SUB} = A \cdot C_{DM1S} = 480\mu^2 \cdot 27\text{aF}\mu^{-2} = 13.0\text{fF}$$

End of Lecture 11